

# RELIABILITY REPORT





NOW PART OF



# Reliability Data Report

## Product Family R523

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LTC3307 \ LTC3308 \ LTC3309 \ LTC3310 \ LTC3311 \ LTC3315  
\ LTC7510 \ LTC7520

## Reliability Data Report R523

Report generated on: Thu Feb 25, 2021

• OPERATING LIFE TEST (JESD22- A108)					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+150°C)	No. of FAILURES
LQFP	462	1726	2033	462.00	0
	462			462.00	0
• BIASED HIGHLY ACCELERATED STRESS TEST AT +130°C/85%RH (JESD22-A110)					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+85°C)	No. of FAILURES
LQFP	385	1726	1821	739.20	0
	385			739.20	0
• UNBIASED HIGHLY ACCELERATED STRESS TEST AT +130°C/85%RH (JESD22-A118)					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+85°C)	No. of FAILURES
LQFP	456	1726	1821	875.52	0
	456			875.52	0
• TEMPERATURE CYCLE FROM -65°C to +150°C (JESD22- A104)					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
LQFP	535	1726	1821	535.00	0
	535			535.00	0
• THERMAL SHOCK FROM -65°C to +150°C (JESD22-A106)					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
LQFP	515	1726	1821	515.00	0
	515			515.00	0
• HIGH TEMPERATURE BAKE +150°C (JESD22-A103)					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
LQFP	381	1726	1821	381.00	0
	381			381.00	0

(1) Assumes Activation Energy = 0.7 Electron Volts  
(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 7.63 FITS  
(3) Mean Time Between Failure in Years = 14,959  
Note 1: 1 FIT = 1 Failure in One Billion Hours  
Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL Preconditioning